

238A 60V N-Channel Enhancement Mode Power MOSFET

General Description

These N-channel enhancement mode power mosfets used advanced trench technology design, provided excellent $R_{DS(on)}$ and low gate charge. Which accords with the RoHS standard.

Features

- Fast switching
- Low reverse transfer capacitances
- Low gate charge and Low on-resistance
- 100% avalanche tested

Mechanical Data

- Case:TO-220 Package

Application

- Power switching applications
- Inverter management system
- Electric tools

Ordering Information

Part No.	Package Type	Package	Quality(box)
D230N06	TO-220	Tube	1000

Product Summary			
V_{DS}	$R_{DS(on)}$ (m Ω) Typ	I_D (A)	Q_g (Typ)
60V	2.6 @ 10V 75A	238	155nc



Block Diagram

Pin Definition:

1. Gate
2. Drain
3. Source

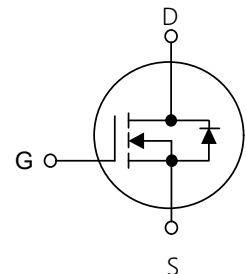


Table1 Absolute Maximum Ratings (Tc=25°C, unless otherwise specified)

Parameter	Symbol	D230N06	Unit
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	Tc=25°C	238
		Tc=100°C	167
Pulsed Drain Current (Note 1)	I_{DM}	952	A
Single Pulse Avalanche Energy(Note 2)	E_{AS}	2025	mJ
Avalanche Current(Note 2)	I_{AR}	90	A
Power Dissipation Tc=25°C	P_D	312	W
Operating Junction and Storage Temperature	T_J/T_{STG}	-55~+175	°C

Table 2. Thermal Characteristics

Parameter	Symbol	D230N06	Unit
Thermal resistance Junction to Ambient	$R_{\theta JA}$	75	$^{\circ}\text{C}/\text{W}$
Thermal resistance Junction to Case	$R_{\theta JC}$	0.48	$^{\circ}\text{C}/\text{W}$

 Table 3. Electrical Characteristics ($T_c=25^{\circ}\text{C}$, unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit	
Off Characteristics							
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu\text{A}$	60	-	-	V	
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=100V, V_{GS}=0V$	-	-	1	μA	
Gate- Source Leakage Current	Forward	I_{GSS}	$V_{GS}=20V, V_{DS}=0V$	-	-	100	nA
	Reverse	I_{GSS}	$V_{GS}=-20V, V_{DS}=0V$	-	-	-100	nA
On Characteristics(Note 3)							
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2.0	-	4.0	V	
Static Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=75A$	-	2.6	3.4	$\text{m}\Omega$	
Dynamic Characteristics(Note 4)							
Input Capacitance	C_{ISS}	$V_{DS}=30V, V_{GS}=0V, f=1\text{MHz}$	-	7700	-	pF	
Output Capacitance	C_{OSS}		-	685	-	pF	
Reverse Transfer Capacitance	C_{RSS}		-	529	-	pF	
Switching Characteristics (Note 4)							
Turn-On Delay Time	$t_{d(on)}$	$V_{DD}=30V, I_D=15A$ $V_{GS}=10V, R_{GEN}=25\Omega,$	-	110	-	ns	
Turn-On Rise Time	t_r		-	255	-	ns	
Turn-Off Delay Time	$t_{d(off)}$		-	330	-	ns	
Turn-Off Fall Time	t_f		-	225	-	ns	
Total Gate Charge	Q_G	$V_{DS}=30V, I_D=45A,$ $V_{GS}=10V$	-	155	-	nC	
Gate-Source Charge	Q_{GS}		-	47	-	nC	
Gate-Drain Charge	Q_{GD}		-	45	-	nC	
Drain-Source Diode Characteristics and Maximum Ratings							
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_S=30A$	-	-	1.3	V	
Maximum Continuous Drain-Source Diode Forward Current	I_S		-	-	160	A	
Reverse Recovery Time	t_{rr}	$V_{GS}=0V, I_F=90A$	-	32	-	ns	
Reverse Recovery Charge	Q_{RR}	$dI_F/dt=100A/\mu\text{s}$ (Note 1)	-	30	-	nC	

Notes: 1 Repetitive Rating:Pulse width limited by maximum junction temperature

 2 $L=0.5\text{mH}, I_D=90A, V_{DD}=50V, V_{GATE}=60V, \text{Starting } T_J=25^{\circ}\text{C}$

 3 Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$

4 Guaranteed by design, not subject to production

Typical Characteristics Diagrams

Figure 1. Output Characteristics

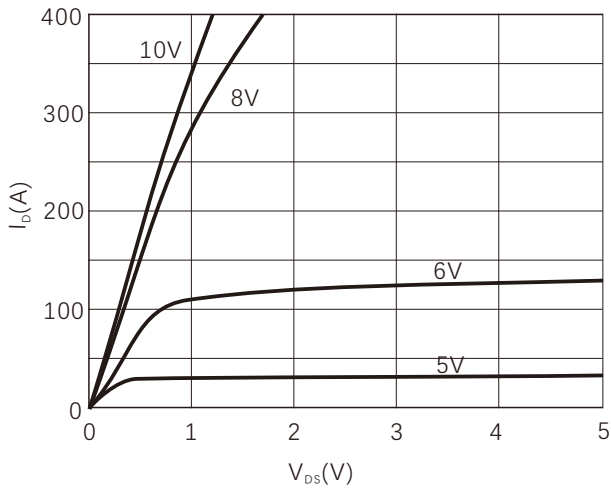


Figure 2. Transfer Characteristics

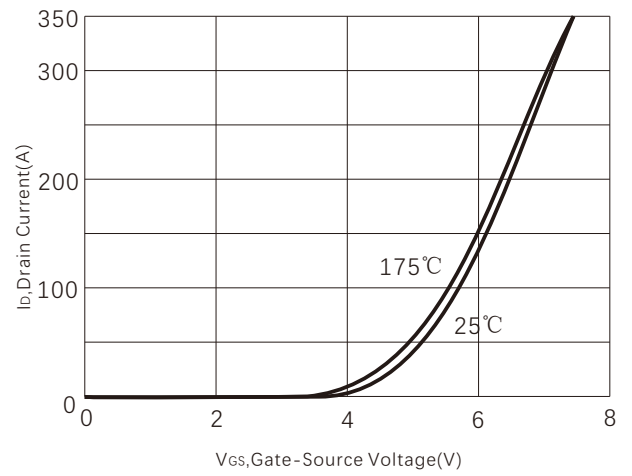


Figure 10. Drain Current vs Case Temperature

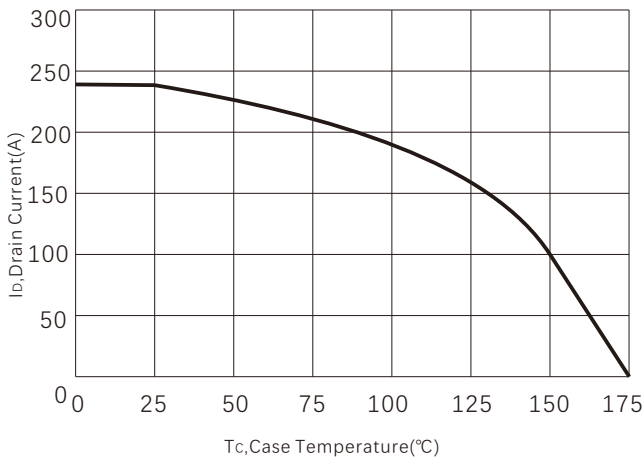


Figure 4. Capacitance

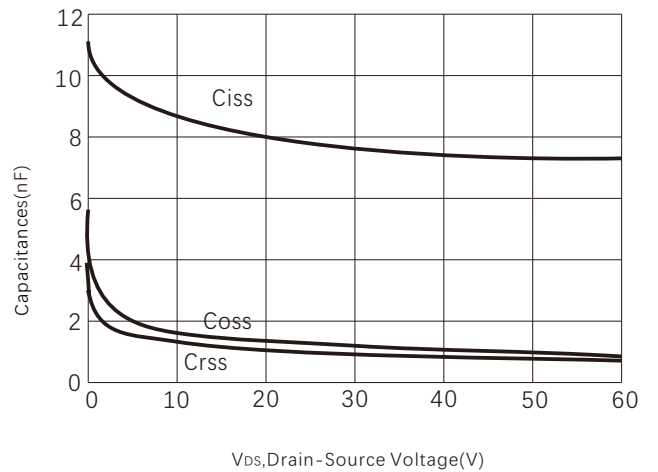


Figure 5. Gate charge

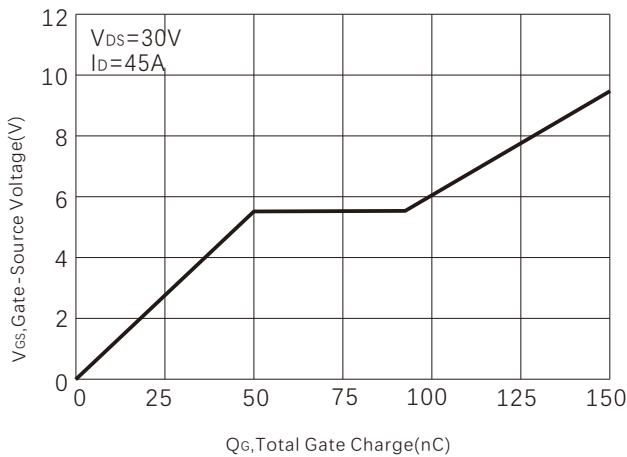


Figure 6. Source-Drain Diode Forward Voltage

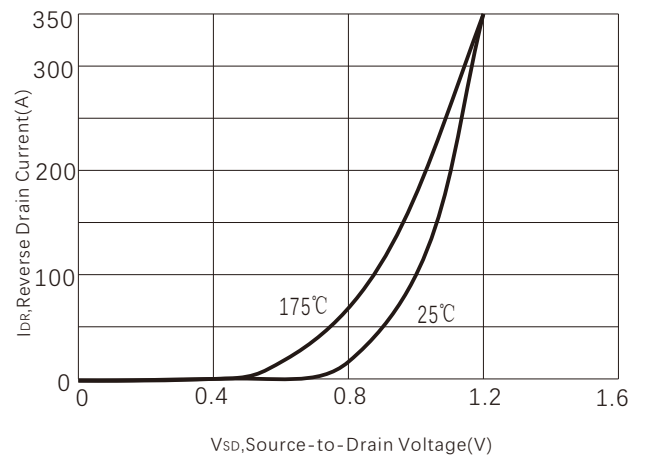


Figure 7. $R_{DS(ON)}$ vs Junction Temperature

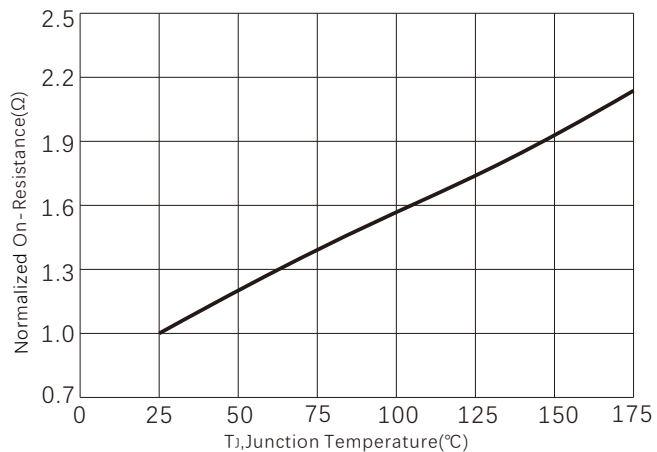


Figure 8. Power dissipation

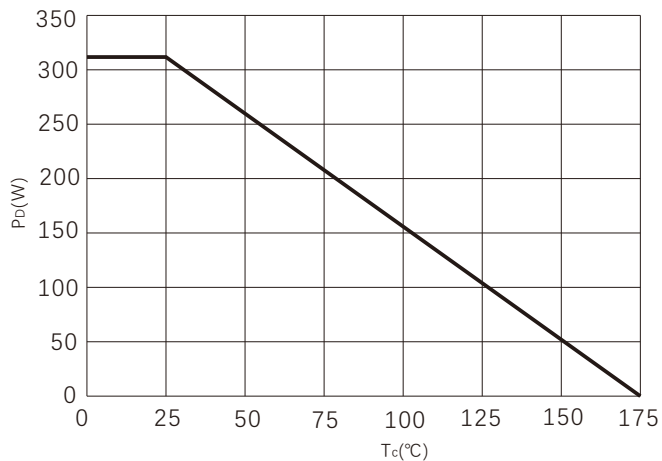


Figure 9. Safe operating area

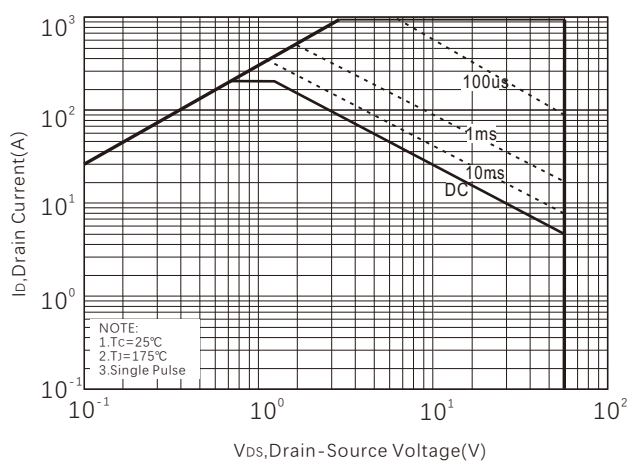
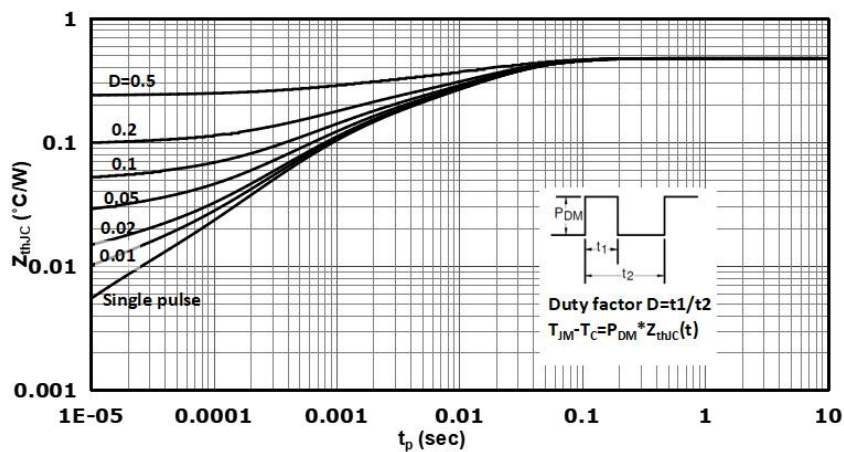
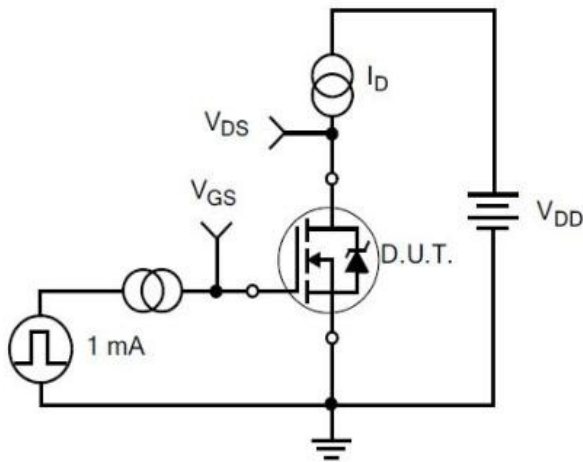


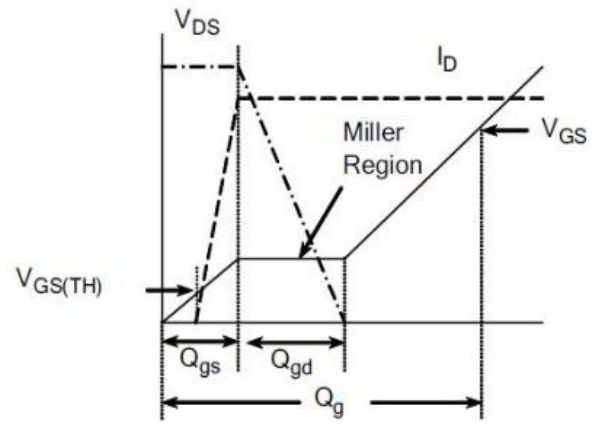
Figure 10. Maximum Transient Thermal Impedance



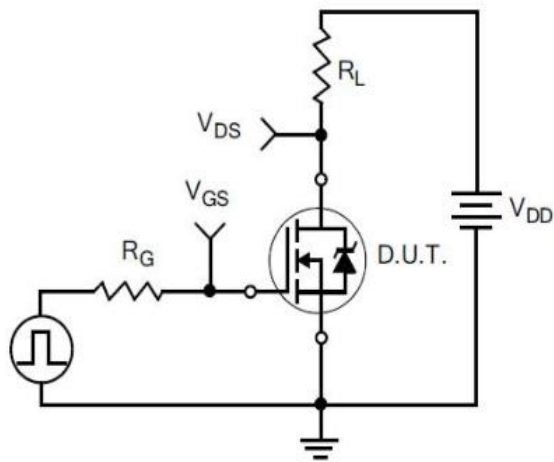
Typical Test Circuit



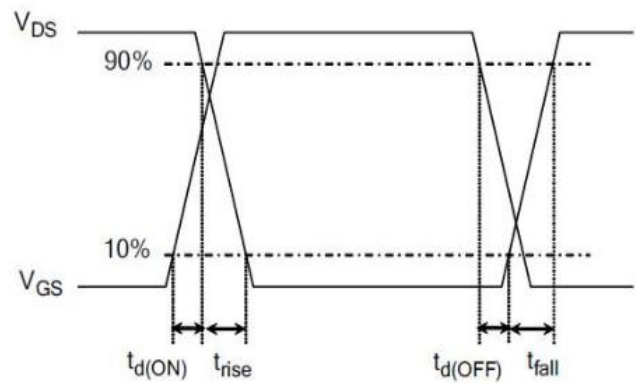
1) Gate Charge Test Circuit



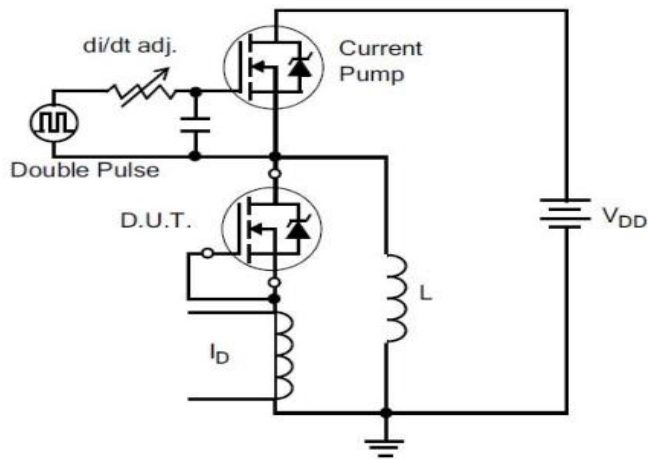
2) Gate Charge Waveform



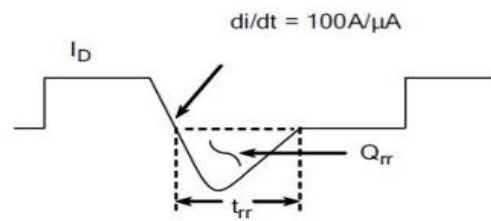
3) Resistive Switching Test Circuit



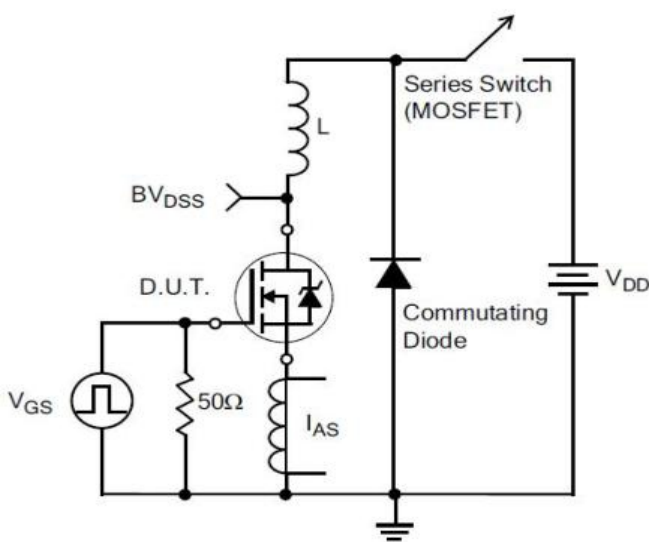
4) Resistive Switching Waveforms



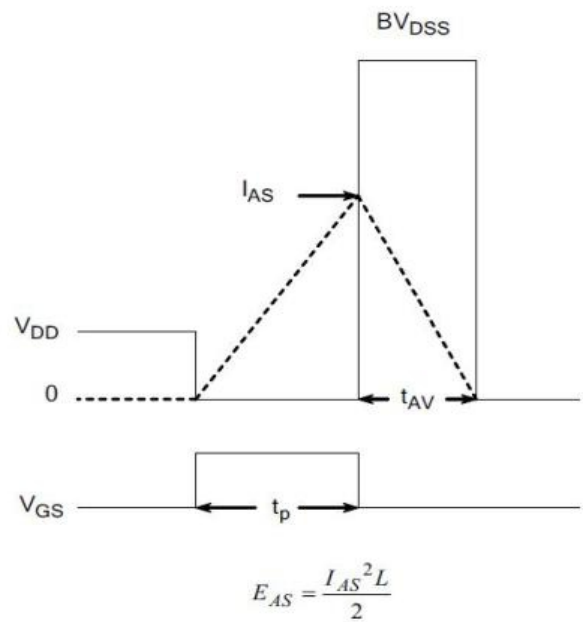
5) Diode Reverse Recovery Test Circuit



6) Diode Reverse Recovery Waveform



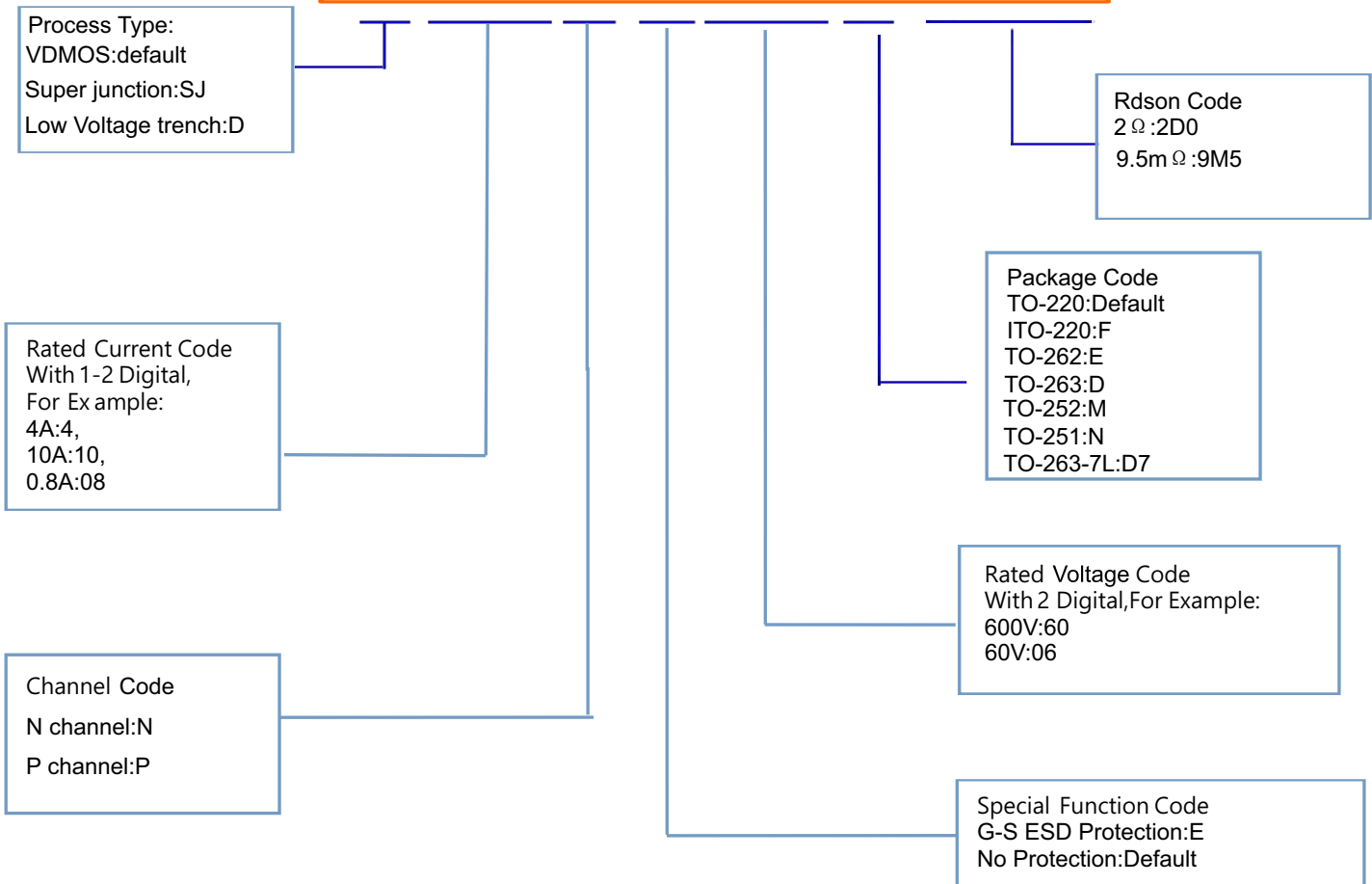
7) . Unclamped Inductive Switching Test Circuit



8) Unclamped Inductive Switching Waveforms

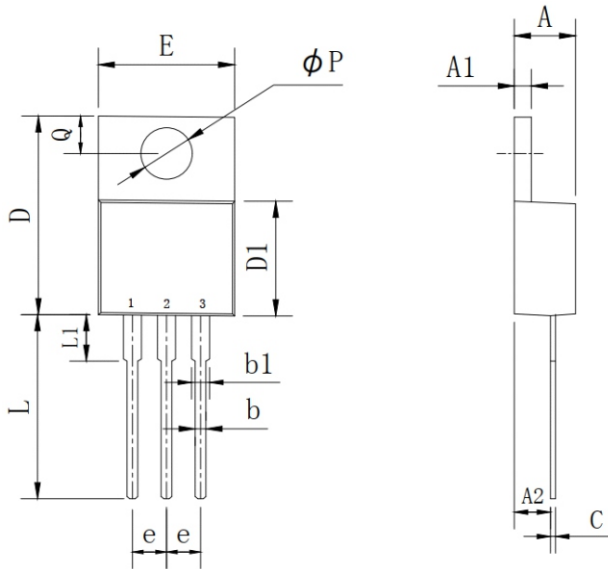
Product Names Rules

X X X N E X X X-X X X



Dimensions

TO-220 PACKAGE OUTLINE DIMENSIONS



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	MIN	MAX	MIN	MAX
A	4.25	4.87	0.167	0.192
A1	1.07	1.47	0.042	0.058
A2	2.03	2.92	0.080	0.115
b	0.51	1.11	0.020	0.044
b1	0.97	1.6	0.038	0.063
C	0.3	0.7	0.012	0.028
D	14.6	15.9	0.575	0.626
D1	8.04	9.3	0.317	0.366
E	9.57	10.57	0.377	0.416
e	2.34	2.74	0.092	0.108
L	12.58	14.3	0.495	0.563
L1	2.8	4.2	0.110	0.165
P	3.4	4.14	0.134	0.163
Q	2.45	3	0.096	0.118

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